

SCIENTIFIC REPORTS

OPEN

Erratum: Determination of Low Loss in Isotopically Pure Single Crystal ^{28}Si at Low Temperatures and Single Microwave Photon Energy

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Scientific Reports 7:44813; doi: 10.1038/srep44813; published online 20 March 2017; updated on 20 September 2017

The original version of this Article contained typographical errors in the Abstract.

“Whispering Gallery Mode (WGM) analysis revealed large Quality Factors of order 2×10^6 (dielectric loss $\sim 5 \times 10^{-7}$) at high powers, degrading to 7×10^{-5} (dielectric loss $\sim 1.4 \times 10^{-6}$ at single photon energy. A very low-loss narrow line width paramagnetic spin flip transition was detected with extreme sensitivity in ^{28}Si , with very small concentration below 10^{10} cm^{-3} (less than 10 parts per trillion) and g-factor of 1.995 ± 0.008 ”.

now reads:

“Whispering Gallery Mode (WGM) analysis revealed large Quality Factors of order 2×10^6 (dielectric loss $\sim 5 \times 10^{-7}$) at high powers, degrading to 7×10^5 (dielectric loss $\sim 1.4 \times 10^{-6}$) at single photon energy. A very low-loss narrow line width paramagnetic spin flip transition was detected with extreme sensitivity in ^{28}Si , with very small concentration below 10^{11} cm^{-3} (less than 10 parts per trillion) and g-factor of 1.995 ± 0.008 ”.

This has now been corrected in the PDF and HTML versions of the Article.



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